10W, 28V High Power RF LDMOS FETs

Description

The M8M1001 is a 10-watt, highly rugged, unmatched LDMOS FET, designed for wide-band commercial and industrial applications at frequencies up to 2 GHz. It can be used in Class AB/B and Class C for all typical modulation formats.

Typical Performance (On Innogration fixture with device soldered):

 $V_{DD} = 28 \text{ Volts}, I_{DQ} = 100 \text{ mA}, CW.$

Frequency	Gp (dB)	P _{-1dB} (W)	η _D @P ₋₁ (%)	
960 MHz	23	13	63	

•Typical Performance (On Innogration fixture with device soldered):

 $V_{DD} = 12 \text{ Volts}, I_{DQ} = 10 \text{ mA}, CW.$

Frequency	Gp (dB)	P _{-1dB} (W)	η _D @P ₋₁ (%)
120 MHz	13	5	58

Features

- High Efficiency and Linear Gain Operations
- Integrated ESD Protection
- Excellent thermal stability, low HCI drift

- Large Positive and Negative Gate/Source Voltage Range for Improved Class C Operation
- Pb-free, RoHS-compliant

Suitable Applications

- 2-30MHz (HF or Short wave communication)
- 30-88MHz (Ground communication)
- 54-88MHz (TV VHF I)
- 88-108MHz (FM)
- 118 -140MHz (Avionics)

- 136-174MHz (Commercial ground communication)
- 160-230MHz (TV VHF III)
- 30-512MHz (Jammer, Ground/Air communication)
- 470-860MHz (TV UHF)
- 100kHz 1000MHz (ISM, instrumentation)

Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
DrainSource Voltage	V _{DSS}	+95	Vdc
GateSource Voltage	$V_{\sf GS}$	-10 to +10	Vdc
Operating Voltage	V _{DD}	+40	Vdc
Storage Temperature Range	Tstg	-65 to +150	°C
Case Operating Temperature	T _c	+150	°C
Operating Junction Temperature	T₃	+225	°C

Table 2. Thermal Characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case	Do 10	2	0000
T _C = 85°C, T _J =200°C, DC test	Rejc	3	°C/W

Table 3. ESD Protection Characteristics

Test Methodology	Class
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Human Body Model (per JESD22A114)			Class 2			
Table 4. Electrical Characteristics (TA = 25 °C unless otherwise noted)						
Characteristic	Symbol	Min	Тур	Max	Unit	
DC Characteristics						
Drain-Source Voltage	V		0.5			
V_{GS} =0, I_{DS} =1.0mA	$V_{(BR)DSS}$		95		V	
Zero Gate Voltage Drain Leakage Current				4	^	
$(V_{DS} = 75V, V_{GS} = 0 V)$	I _{DSS}			1	μΑ	
Zero Gate Voltage Drain Leakage Current				4	^	
$(V_{DS} = 28 \text{ V}, V_{GS} = 0 \text{ V})$	I _{DSS}			1	μΑ	
GateSource Leakage Current				4	^	
$(V_{GS} = 10 \text{ V}, V_{DS} = 0 \text{ V})$	I _{GSS}			1	μΑ	
Gate Threshold Voltage	V (II)		0.07		V	
$(V_{DS} = 28V, I_D = 50 \mu A)$	V _{GS} (th)		2.07		V	
Gate Quiescent Voltage	V		2.2		V	
$(V_{DD} = 28 \text{ V}, I_D = 100 \text{ mA}, Measured in Functional Test)$	$V_{GS(Q)}$		3.3		V	
Common Source Input Capacitance			TDD		, r	
$(V_{GS} = 0V, V_{DS} = 28 V, f = 1 MHz)$	C _{ISS}	TBD			pF	
Common Source Output Capacitance			TDD			
$(V_{GS} = 0V, V_{DS} = 28 V, f = 1 MHz)$	Coss		TBD		pF	
Common Source Feedback Capacitance					_	
$(V_{GS} = 0V, V_{DS} = 28 V, f = 1 MHz)$	C_{RSS}		TBD		pF	
Functional Tests (In Demo Test Fixture, 50 ohm system) V _{DD} = 28 V	$^{\prime}$ dc, $I_{DQ} = 100$ mA,	f = 960 MHz,	CW Signal Me	asurements.		
Power Gain	Gp		23		dB	
Drain Efficiency@P1dB	η _D		63		%	
1 dB Compression Point	P _{-1dB}		13		W	
Input Return Loss	IRL		-7		dB	
Load Mismatch (In Innogration Test Fixture, 50 ohm system): V _{DD} = 28 Vdc, I _{DQ} = 100 mA, f = 960 MHz						
VSWR 20:1 at 13W pulse CW Output Power No Device Degradation						

TYPICAL CHARACTERISTICS

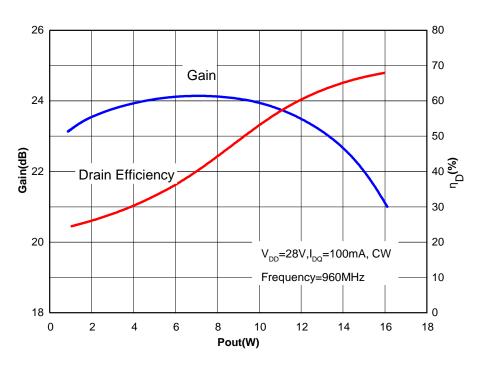


Figure 1. Power gain and drain efficiency as function of Power out

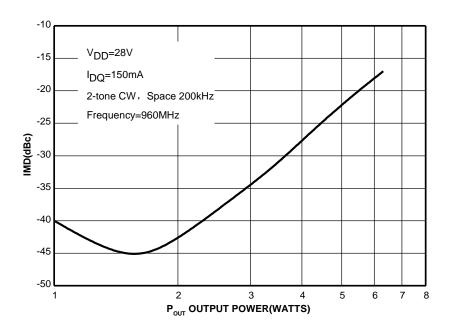
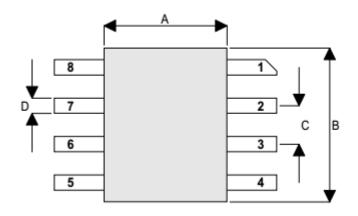


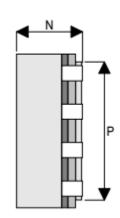
Figure 2. IMD3 versus Output Power

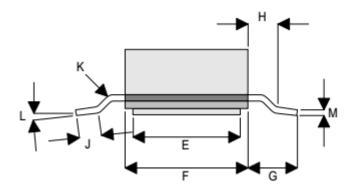
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Package Outline

SO8 Ceramic package; Gull-wing 8 leads







Pin Connection

Pin1—Source	Pin5—Source			
Pin2—Drain	Pin6—Gate			
Pin3—Drain	Pin7—Gate			
Pin4—Source	Pin8—Source			
Bottom—Source				

UNIT	Α	В	С	D	E	F	G	Н	J	к	L	М	N	Р
mm	4.06	5.08	1.27	0.51	3.56	4.06	1.65	0.76	0.51 1.02	45°	0° 7°	0.20	2.18	4.57
Tol.	±0.08	±0.08	±0.08	±0.08	±0.08	±0.08	±0.08	0.25 0	Min. Max.	Max.	Min. Max.	±0.08	±0.08	±0.08
Inches	0.160	0.200	0.050	0.020	0.140	0.160	0.065	0.030	0.020 0.040	45°	0° 7°	0.008	0.086	0.180
Tol.	±0.003	±0.003	±0.003	±0.003	±0.003	±0.003	±0.003	0.010 0	Min. Max.	Max.	Min. Max.	±0.003	±0.003	±0.003

OUTLINE		REFERENCE	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	IOGGE DATE
PKG-M8G					5/6/2017

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Revision history

Table 5. Document revision history

Date	Revision	Datasheet Status
2018/12/17	Rev 1.0	Preliminary Datasheet

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